

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination WANG ET AL.	
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*	B	US-6,884,333	04-2005	Landau, Uziel	205/81
*	C	US-5,217,112	06-1993	Almon, Amy C.	205/794.5
*	D	US-4,172,777	10-1979	Yamamoto et al.	204/406
*	E	US-6,187,164	02-2001	Warren et al.	205/81
*	F	US-6,251,245	06-2001	Satsutani et al.	204/416
*	G	US-5,445,726	08-1995	Cammann, Karl	205/780.5
*	H	US-4,166,020	08-1979	Trampert, Hans R.	204/416
*	I	US-6,106,692	08-2000	Kunimatsu et al.	205/775
*	J	US-4,863,572	09-1989	Jasinski, Raymond J.	205/775.5
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yabe et al. ("Rotating Ring Disk Electrode in Molten Chloride," <i>Electrochimica Acta</i> , Vol. 34, No. 10, pp. 1479-1483, 1989)
	V	Strycker et al. ("Development of a platinum rotating disc electrode for dynamic electrochemical measurements in glass melts," <i>Journal of Non-Crystalline solids</i> 289 (2001) 106-112)
	W	Stojanovic et al. ("Development of a rotating ring-disc electrode for high temperature studies in cryolite-based melts," <i>Journal of Applied Electrochemistry</i> 25 91995) 456-461)
	X	Ito et al. ("Rotating Ring Disk Electrode in Molten Chloride Systems," <i>Materials Science Forum</i> vol. 73 - 75 (1991) pp. 409-414)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	V	"coating" definition from Webster's Third New International Dictionary, unabridged. 1993.
	W	Chemical Elements.com – Molybdenum downloaded from www.chemicalelements.com on March 20, 2007
	X	Chemical Elements.com – Gold downloaded from www.chemicalelements.com on March 20, 2007

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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